



From the equations it is clear that one needs to maximize  $gm/ID_1$  and  $gm/ID_2$  to get the highest gain. At the same time, it is desirable to have sufficiently large B and  $ID_1$  to meet the SR requirements ( $>10$  MV/s). While trying to adjust for these two metrics, it is also important to keep in mind the phase margin (PM) to ensure stable operation. Lastly, we derive another formulation of the small-signal gain and bandwidth (BW) equations that would prove to be useful later in the design space exploration stage:

$$R_{out} = R_{down} || R_{up} \quad \text{assume} \quad R_{down} = R_{up} \rightarrow R_{out} = \frac{R_{down}}{2}$$

$$V_X - I_X * r_{o7} = (I_X - g_{m6,7}V_{GS}) * r_{o7} = (I_X + g_{m6,7}I_X r_{o6}) * r_{o7}$$

$$R_{down} = \frac{V_X}{I_X} = g_{m6,7}r_{o7}r_{o6} + r_{o7} + r_{o6}$$

$$A_0 = g_{m1,2}R_{out} = \frac{1}{2}g_{m1,2} * (g_{m6,7}r_{o7}r_{o6} + r_{o7} + r_{o6})$$

$$BW = \frac{1}{2\pi R_{out}C_L} = \frac{1}{\pi * (g_{m6,7}r_{o7}r_{o6} + r_{o7} + r_{o6}) * C_L}$$

The BW expression was derived assuming that the dominant pole is at the output governed by  $C_L$ . These expressions are key because they show us the inverse squared relation ( $r_o \propto 1/ID$ ) between the gain and the output stage current, which is set by B - the SR parameter. Furthermore, it exposes the direct tradeoff between the DC gain and BW and our knob is  $ID$  of the output stage.

## Transistor characterization

The next step is to choose the desired transistor type (SVT, LVT, HVT) from the PDK (we use **GPDK45**) and generate  $gm/ID$  plots. Due to their lower  $V_{TH}$  we decided to proceed with LVT devices. The setup and the resulting graphs are depicted on Fig. 2-4. We fixed the width of the transistors to 1  $\mu$ m and swept the length from 45 nm to 180 nm. The VDS across transistor was kept at  $VDD/2$  following the convention.

## OTA design procedure

Now that we have the look-up plots, we can proceed onto the design stage. In order to maximize both gain and bandwidth, which is our target here, one has to burn a lot of power. In this way, we chose to have  $ID_1 = 11$   $\mu$ A and  $B = 6$  so as to stay within the provided current supply limits (100  $\mu$ A). Then we can figure out the SR:

$$SR = \frac{11e^{-6} * 6}{2e^{-12}} = 33 \text{ MV/s}$$

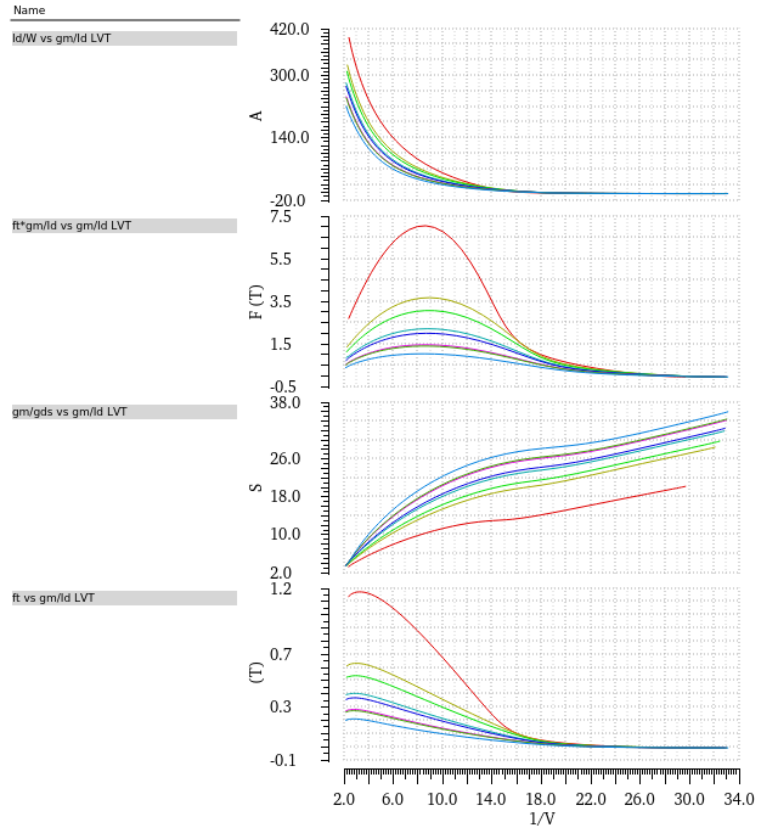
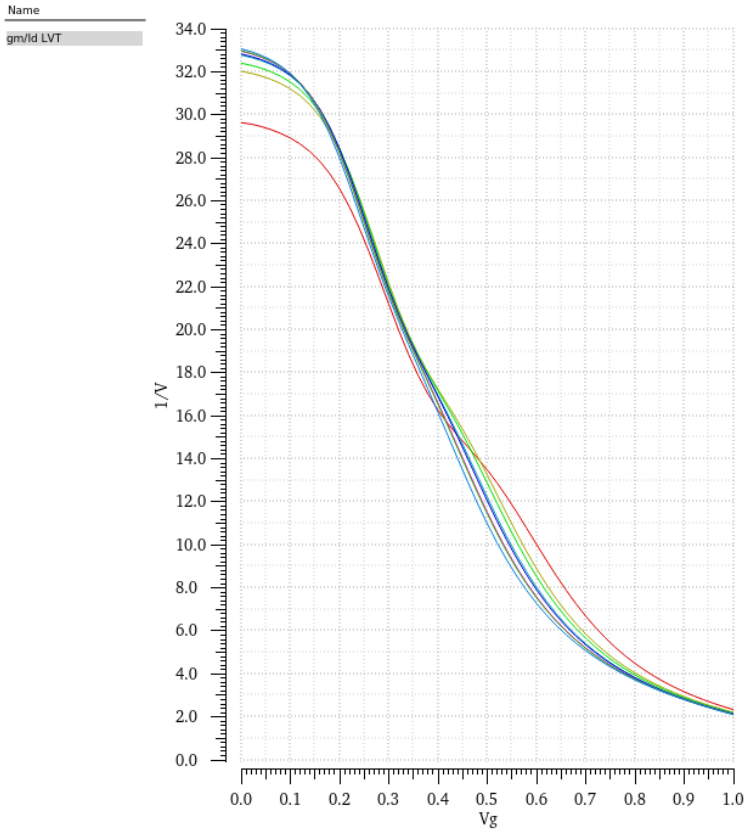


FIGURE 2. GM/ID PLOT FOR NMOS LVT.

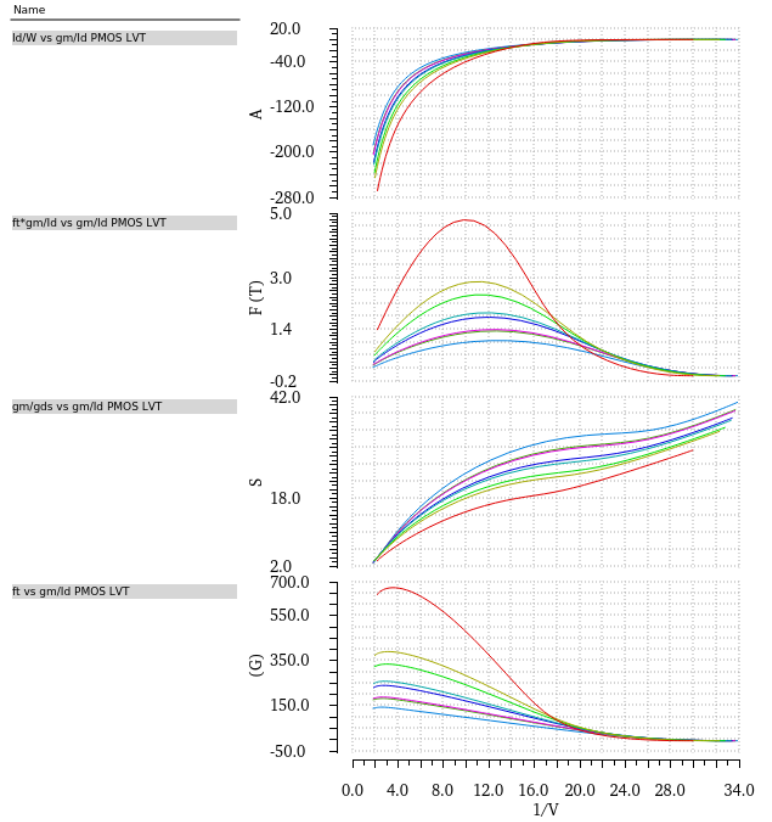
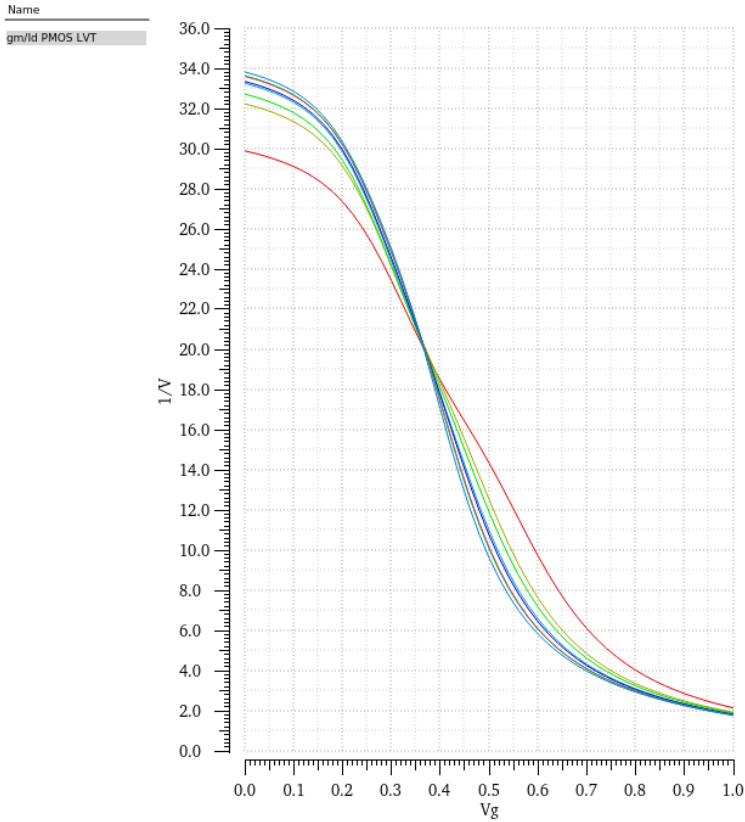
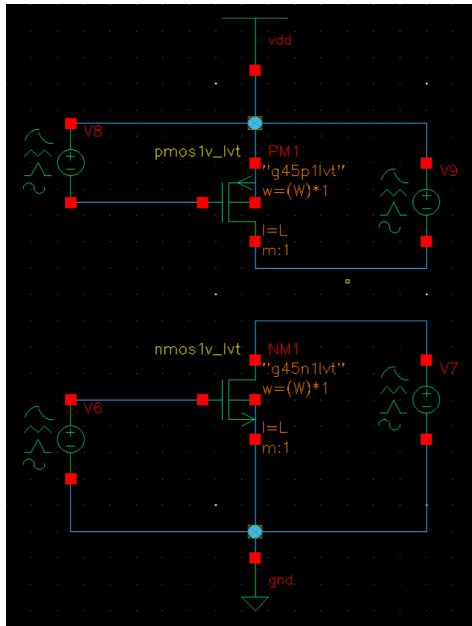


FIGURE 3. GM/ID PLOT FOR PMOS LVT.



**FIGURE 4. TRANSISTOR CHARACTERIZATION SETUP IN CADENCE.**

Transistor	W/L theoretical (nm/nm)	W/L adjusted (nm/nm)
<b>M1,2</b>	3972/180	4080/180
<b>M3,4,5</b>	621/180	600/180
<b>M6</b>	3726/180	4200/180
<b>M7</b>	9897/90	9960/90
<b>M8</b>	621/180	580/180
<b>M9</b>	3726/180	4060/180
<b>M10</b>	7765/90	7800/90
<b>M11</b>	1650/90	1560/90
<b>M12</b>	1165/180	2160/180

**TABLE 1. DEVICE SIZING.**

Now we pick our  $g_m/I_D$  for the input pair. To maximize it, we decided to keep the length of the input pair as well as the current mirror transistors  $L = 180 \text{ nm}$ , since this allows much lower threshold voltage and hence higher  $g_m/I_D$ . Thus, based on the  $V_{TH}$  of transistor we select the highest  $g_m/I_D$  that still allows us to be above the threshold voltage. In other words, we operate the input pair in the weak-moderate inversion.  $V_{TH}$

for 180 nm transistors is around 330-350 mV and according to Fig. 3-4 (left-side images), if we operate just above it we can get **gm/ID of 21 S** for the input pair. Because we know the current through the differential pair, we can easily compute the widths of the transistors using the current density plot:

$$W_{1,2} = \frac{I_{D1}}{I_D/W} = \frac{11e^{-6}}{2.76944} = 3972 \text{ nm}$$

Next, we turn our attention to the current source transistors. We group them together to have the same gm/ID. The PMOS current source M12 should provide 22 uA current while having high output impedance. For this reason, it's best to operate it in the strong inversion. We set **gm/ID = 11 S** (strong inversion) for all current source transistors and find their W based on their drain current. Following the same math as before, we tabulate all the sizes in Table 1. We also put the sizes for the cascode devices (M7,10,11). The cascode devices' L = 90 nm to lower the threshold voltage and access higher gm/ID in weak-moderate region to maximize the gain. Using the same principle as before (i.e. selecting highest gm/ID that is still above  $V_{TH}$ ), we set **gm/ID = 16 S** for the cascode devices. After sizing all the devices, we made further adjustment to fine-tune the current values in each branch and make sure every transistor operates in saturation. As can be concluded from Table 1, the final sizes for all devices agree very

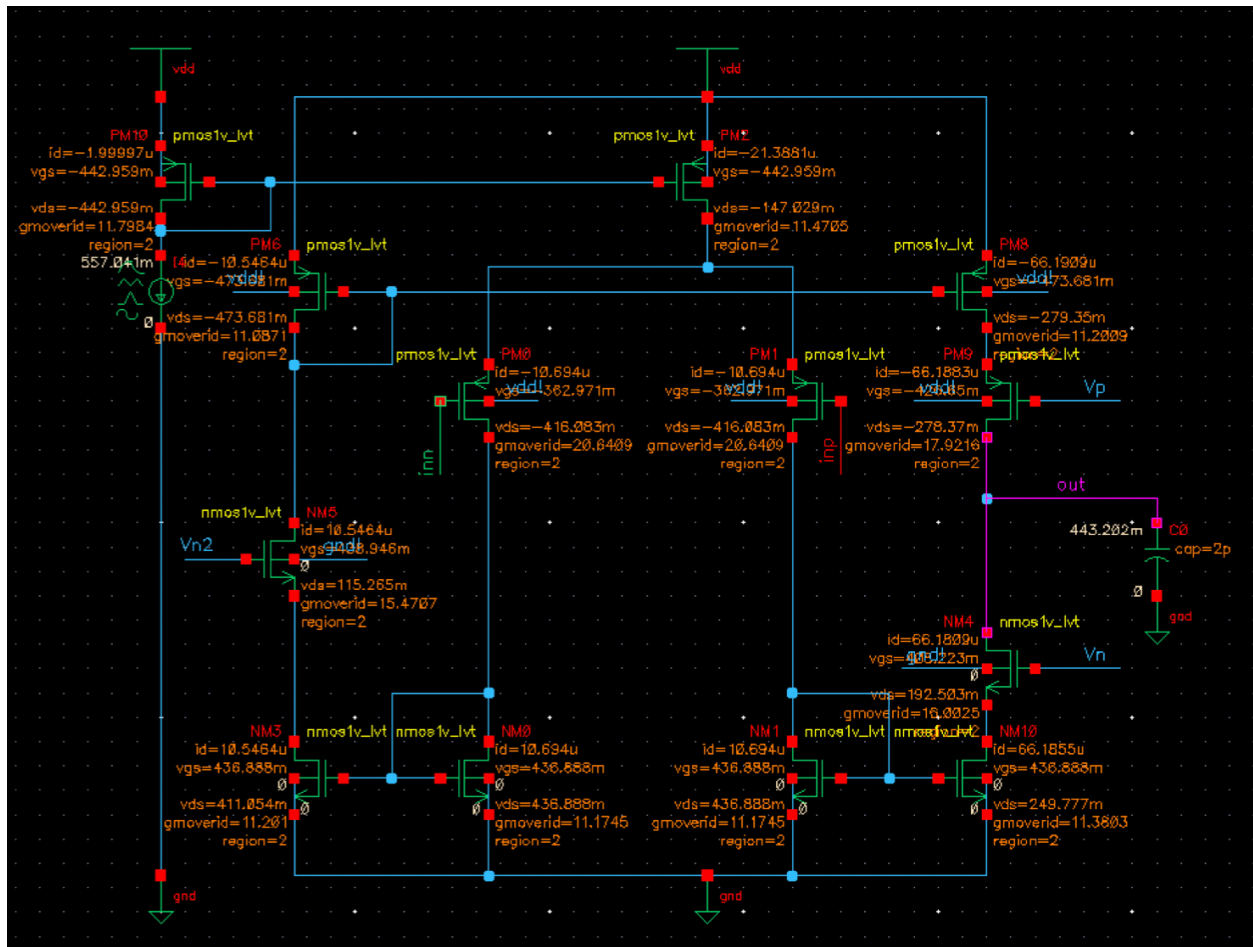


FIGURE 5. CADENCE SCHEMATIC OF THE OTA.

well with the pre-computed ones, all but M6,9, and M12. For M12 we had to increase the size significantly because it was consuming too much  $V_{DS}$ . In the case of M6,9 we had to set B to 7 instead of 6 to achieve 66  $\mu A$  current on the output stage. The final tweaks has to be made to the biasing voltages of M7,10,11 as well as the input pair. For the latter, we decided to have  $V_{in,bias} = 490 \text{ mV}$  to achieve the set  $gm/ID$  while preserving the current sources in saturation. M11 was biased based on its drain and source voltages so as to keep it in saturation while maximizing the  $V_G$  ( $V_{n2} = 850 \text{ mV}$ ). For M7 and M10:

$$M10 : V_G - V_S \leq V_{TH} \quad \rightarrow \quad V_G \leq 719mV - 425mV = 294mV$$

$$M7 : V_G - V_S \geq V_{TH} \quad \rightarrow \quad V_G \geq 252mV + 406mV = 658mV$$

We plug-in these numbers for the  $V_n$  and  $V_p$ . If one tries to increase  $V_n$  and decrease  $V_p$  further, this will cause reduction in the output swing coming from the saturation condition equations. Note that we obtain the  $V_S$  and  $V_{TH}$  values from simulations.

## Results

The results of simulation are shown in Fig. 6-9. The performance of the circuit is numerically provided in Table 2. Thus, as can be seen from the results, we successfully met all the specifications and achieved very high gain as well as high BW, though at the cost of maximum power consumption and area. Overall, this report proved that it is possible to achieve one's target specifications within merely a few iterations using the  $gm/ID$  methodology.

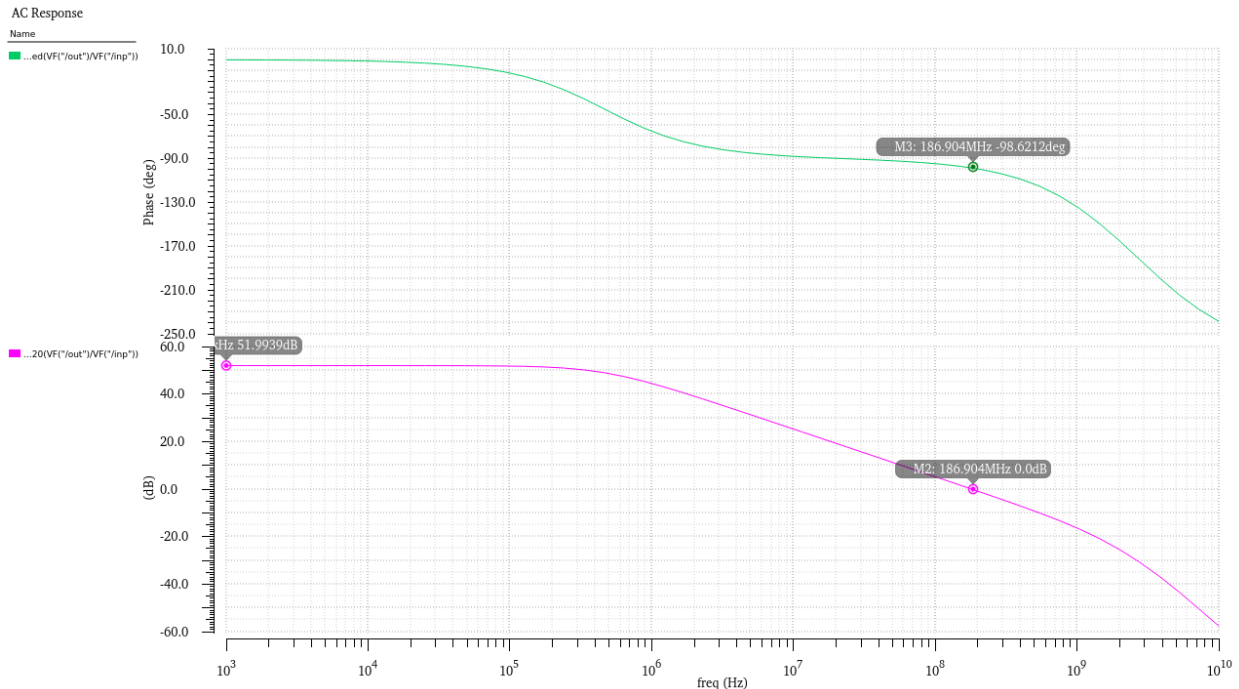


FIGURE 6. GAIN AND PHASE PLOTS.

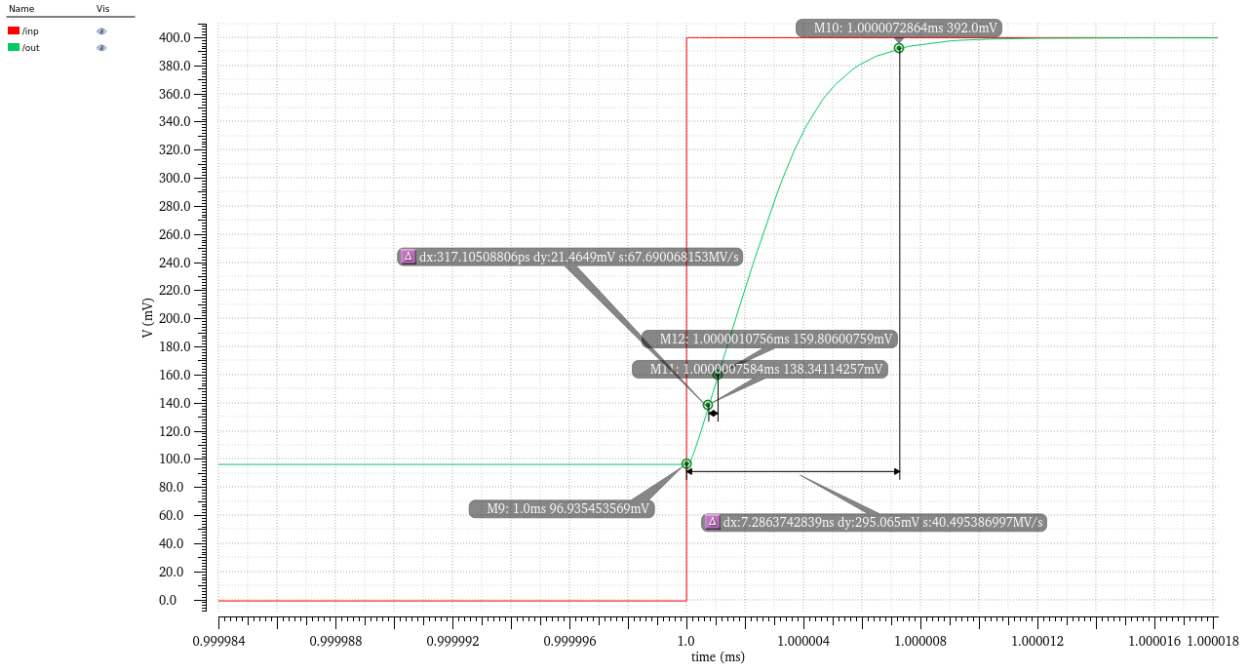


FIGURE 7. CLOSED-LOOP SIMULATION RESULTS FOR SR AND SETTLING TIME.

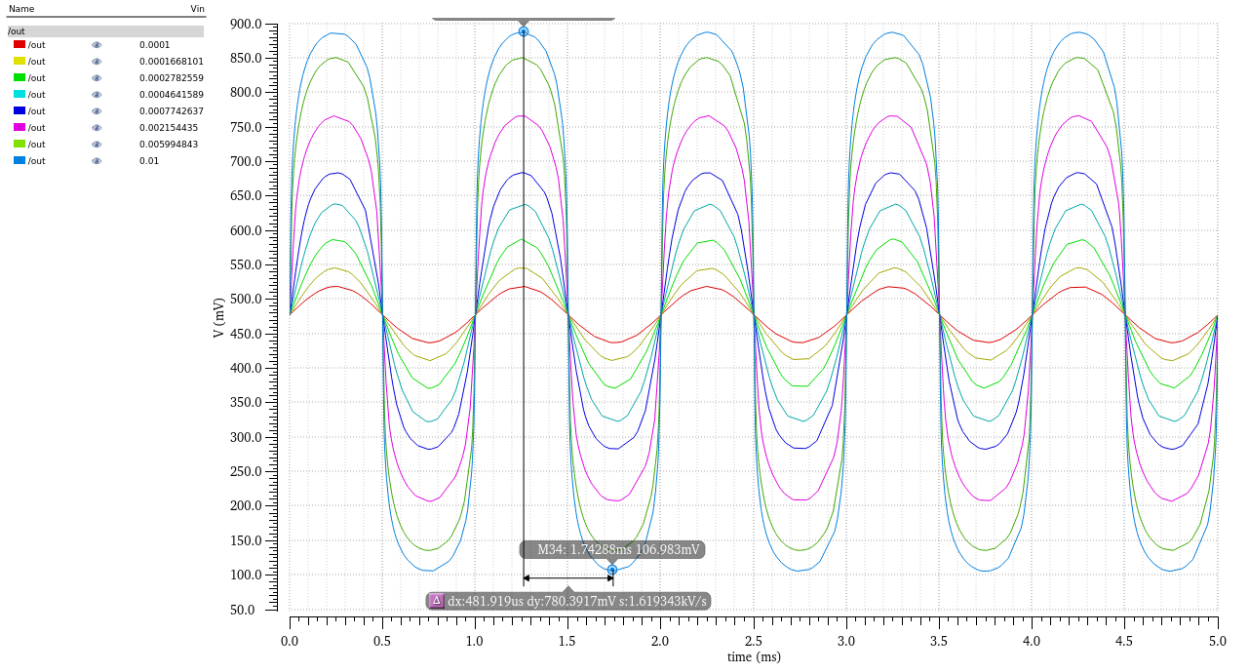
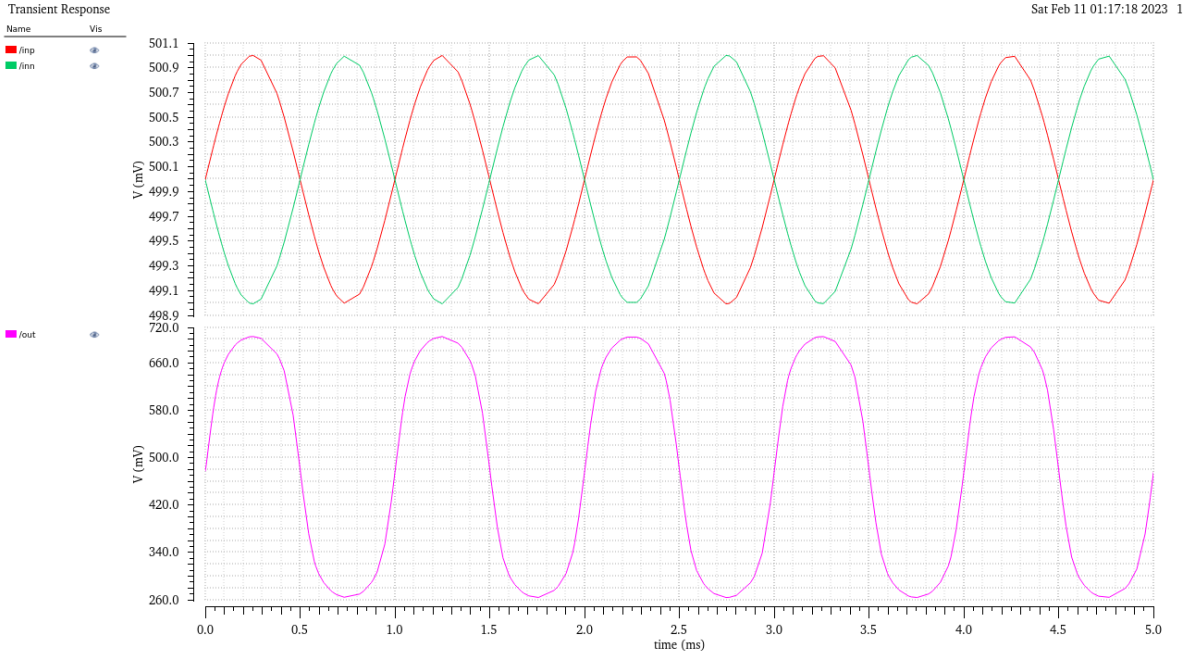


FIGURE 8. OUTPUT SWING VS. SMALL-SIGNAL INPUT.





**FIGURE 9. TRANSIENT RESPONSE OF THE OTA AT 1 KHZ INPUT.**

Metric	Our results
DC gain (dB)	52
UGBW (MHz)	186.9
Slew rate (MV/s)	67.7
2% settling time (ns)	7.3
Phase margin (deg)	101
Total power consumption (uW)	99
Total current consumption (uA)	99
Max output swing (mV)	781

**TABLE 2. PERFORMANCE METRICS AND RESULTS.**

## References

- [1] ECEN 474/704 Lab 7: Operational Transconductance Amplifiers. <https://people.engr.tamu.edu/spalermo/ecen474/Lab7.pdf>
- [2] F. Silveira, D. Flandre, and P. G. A. Jespers, "A gm/ID based methodology for the design of CMOS analog circuits and its application to the synthesis of a silicon-on-insulator micropower OTA," *IEEE Journal of Solid-State Circuits*, vol. 31, no. 9, pp. 1314–1319, 1996.